

Subject Codes 1957-1993

AC01	Acoustics	CH01	Channel subsystem architecture
AL01	Algorithms	CH02	Character recognition
AL02	Alloys	CH03	Charge-coupled devices
AL03	Aluminum	CH04	Checkers and chess
AM01	Amplification	CH05	Chemical vapor deposition
AN01	Analytical models	CH06	Chemistry and chemical engineering
AN02	Antimony	CH07	Chromium
AP01	APL	CI01	Circuit and device technology
AR01	Arithmetic and logical unit design	CI02	Circuit theory and analysis
AR02	Arrays	CL01	Clocking
AR03	Artificial intelligence	CO01	Codes and coding
AT01	Atmospheric processes	CO02	Coding theory
AU01	Automata	CO03	Coding, arithmetic
BE01	Beams, charged particle	CO04	Color
BE02	Bearings	CO05	Combinatorial problems
BI01	Biology and biomedical studies	CO06	Communication theory
BI02	Bismuth	CO07	Communication, scientific
BO01	Boltzmann transport equation	CO08	Communications and communication networks
BO02	Boolean algebra	CO09	Compilers and interpreters
BO03	Boundary-scan design	CO10	Complexity
BU01	Built-in self-test (BIST)	CO11	Computation
CA01	Cadmium	CO12	Computational methods
CA02	Capacitance	CO13	Computer applications
CA03	Carrier transport	CO14	Computer architecture
CA04	Carrier transport in small structures	CO15	Computer organization and design
CA05	Cathode-ray tubes	CO16	Computer system availability
CE01	Ceramics		

CO17 Computer-aided design
 CO18 Computer-assisted instruction
 CO19 Computer-controlled manipulators
 CO20 Computers
 CO21 Contacts
 CO22 Control theory and systems
 CO23 Controlled-collapse chip connection (C-4) technology
 CO24 Cooling
 CO25 Copper
 CO26 Corrosion
 CO27 Counters
 CR01 Cryogenics
 CR02 Cryptography
 CR03 Crystals
 DA01 Data transmission
 DA02 Data, structures and accessing
 DA03 Databases
 DA04 Databases, relational
 DE01 Design automation
 DE02 Design verification
 DI01 Dielectrics
 DI02 Difference equations
 DI03 Differential current switch (DCS)
 DI04 Differential equations
 DI05 Diffraction gratings
 DI06 Diffusion
 DI07 Digital computers
 DI08 Diodes
 DI09 Diodes, tunnel
 DI10 Diskette drives
 DI11 Dislocations
 DI12 Display technology
 DO01 Domain walls
 EL01 Electrical conduction
 EL02 Electrodeposition
 EL03 Electroless plating
 EL04 Electroluminescence
 EL05 Electromagnetic interference
 EL06 Electromagnetics
 EL07 Electromechanics
 EL08 Electron diffraction

EL09 Electron microscopy
 EL10 Electron trap characterization
 EL11 Electrophotography
 EL12 Electrostatics
 EN01 Environment
 EQ01 Equalizers
 ER01 Error control and recovery
 ER02 Error correction codes
 ER03 Error detection and correction
 ES01 Esaki tunneling
 ES02 ESCON architecture
 EX01 Expert systems
 FA01 Fabrication
 FA02 Fault tolerance
 FE01 Fermi surface
 FE02 Ferrites
 FE03 Ferroelectrics
 FE04 Ferromagnetic materials
 FI01 Fiber optics
 FI02 Field-effect transistors
 FI03 Films
 FI04 Films, diazo
 FI05 Films, magnetic
 FI06 Films, metal
 FI07 Films, oxide
 FI08 Films, permalloy
 FI09 Films, photographic
 FI10 Films, polymer
 FI11 Films, semiconductor
 FI12 Films, superconducting
 FI13 Films, thin
 FI14 Filters
 FI15 Finite element analysis
 FL01 Flexible-disk technology
 FL02 Fluids and fluid dynamics
 FL03 Fluorescence
 FO01 Formal methods
 FO02 FORTRAN
 FO03 Fourier transforms
 FR01 Fractals
 GA01 Gallium arsenide

GA02 Game theory
GA03 Garnet
GA04 Gas panels
GE01 Geology
GE02 Geometry
GE03 Geophysics
GE04 Germanium
GO01 Gold
GR01 Graph theory
GR02 Graphics
GR03 Graphite
GU01 Gunn effect
HA01 Hall effect
HA02 Handwriting recognition
HA03 Hashing
HE01 Heterojunctions
HE02 Heuristics
HO01 Holography
HO02 Hot-electron effects
HY01 Hydraulics
HY02 Hydrology
I/O1 I/O devices, systems, and technology
IB01 IBM AS/400
IB02 IBM Magnetic Tape SELECTRIC
IB03 IBM SAGE system
IB04 IBM SELECTRIC Composer
IB05 IBM System/360
IB06 IBM System/360, Model 91
IB07 IBM System/370 Extended Architecture (370-XA)
IB08 IBM System/390 ES/9000
IB09 IBM 1975 Optical Page Reader
IB10 IBM 2750
IB11 IBM 305 (RAMAC)
IB12 IBM 350 (RAMAC)
IB13 IBM 608
IB14 IBM 610
IB15 IBM 650
IB16 IBM 7030 (Stretch)
IB17 IBM 704
IB18 IBM 705
IB19 IBM 7090

IB20 IBM 727-III
IB21 IBM 728
IB22 IBM 738
IM01 Image processing
IM02 Imaging technology
IN01 Indium
IN02 Inductance
IN03 Information theory
IN04 Infrared studies
IN05 Instabilities in semiconductors
IN06 Instrumentation
IN07 Insulators
IN08 Integrated circuit design
IN09 Integrated circuits
IN10 Interconnection technology
IN11 Interfaces
IN12 Interferometry
IO01 Iodine
IR01 Iron
JO01 Josephson technology
JU01 Junctions
KN01 Knowledge systems
LA01 Laboratory automation
LA02 Large-scale computing
LA03 Laser arrays
LA04 Lasers
LA05 Lasers, injection
LE01 Lead
LE02 LEED
LI01 Light
LI02 Light, coherent
LI03 Linguistics
LI04 Liquid crystals
LI05 Lithography
LI06 Lithography, electron-beam
LI07 Lithography, X-ray
LO01 Local area networks (LANs)
LO02 Logic
LO03 Logic design and technology
LO04 Logic macros
LO05 Logic programming

LO06	Logic synthesis	MI01	Microelectronics
LS01	LSI	MI02	Micrography
LS02	LSI design automation	MI03	Microprocessor systems and applications
LS03	LSSD design and testing	MI04	Microwaves
LU01	Lubrication	MO01	Models and modeling
MA01	Machine computation and data analysis	MO02	Monte Carlo methods
MA02	Magnetic bubble technology	MU01	Multiplexing
MA03	Magnetic fields	MU02	Multiprocessors
MA04	Magnetic head design	NA01	Natural language processing
MA05	Magnetic head-disk interaction	NE01	Negative resistance/conductivity
MA06	Magnetic head-tape interaction	NE02	Networks
MA07	Magnetic recording	NI01	Nickel
MA08	Magnetic tape	NI02	Niobium
MA09	Magnetics - studies and structures	NO01	Noise
MA10	Magneto-optics	NU01	Numerical integration
MA11	Magnetoresistance	OF01	Office machines and systems
MA12	Management science	OP01	Operating systems
MA13	Manufacturing	OP02	Operations research
MA14	Markov process analysis	OP03	Optical science and technology
MA15	Masers	OP04	Optics
MA16	Masks	OP05	Optimization
MA17	Masks, X-ray	OP06	Optoelectronic device technology
MA18	Mass spectrometers	OS01	Oscillators
MA19	Materials	OS02	Osmium
MA20	Materials technology	PA01	Packaging
MA21	Mathematical functions and techniques	PA02	Paging
MA22	Mathematics	PA03	Parallel processing
MA23	Mathematics (applied)	PA04	Pattern recognition
MA24	Matrix and network studies	PE01	Performance analysis
ME01	Measurement	PE02	Personal computers
ME02	Mechanical analysis	PH01	Photo-processes
ME03	Mechanical design	PH02	Photodetectors
ME04	Mechanics and mechanisms	PH03	Photoemission
ME05	Medicine and medical electronics	PH04	Photography
ME06	Memory (computer) design and technology	PH05	Photoresists
ME07	Memory (computer) management	PH06	Photovoltaic materials
ME08	Memory, cache	PH07	Physical chemistry
ME09	Memory, magnetic core	PH08	Physics
ME10	Memory, random-access	PH09	Physics of semimetals
ME11	Mesoscopic phenomena	PH10	Physics, solid state
ME12	Metallurgy		

PH11	Physics, theoretical	SI07	Silver
PI01	Picosecond measurements	SI08	Simulation
PO01	Polarimetry	SO01	Software reliability
PO02	Polymers	SO02	Solar cells
PO03	Power supplies	SO03	Solar energy
PR01	Printed circuits	SO04	Solder ball connect (SBC) technology
PR02	Printing technology	SO05	Solid logic technology
PR03	Printing, electroerosion	SO06	Solid modeling
PR04	Printing, impact	SP01	Space-related technology
PR05	Printing, ink jet	SP02	Spectroscopy
PR06	Printing, non-impact	SP03	Speech processing
PR07	Printing, thermal transfer	SP04	Sputtering
PR08	Process control and development	ST01	Statistical mechanics
PR09	Programmable logic arrays (PLAs)	ST02	Statistics
PR10	Programming systems	ST03	Stimulated emission
PR11	Programming, programs, and programming languages	ST04	Storage (computer) devices and systems
QU01	Quality control	ST05	Storage hierarchies
QU02	Quantum theory	SU01	Superconductivity
QU03	Queuing theory and applications	SU02	Superconductivity, high-T _c
RA01	Radiative transfer	SU03	Superlattices
RE01	Real-time systems	SU04	Surface effects
RE02	Recording technology	SU05	Surface passivation
RE03	Reduced-instruction-set computers (RISC)	SU06	Surface science
RE04	Relaxation processes	SW01	Switches
RE05	Relays	SW02	Switching circuits
RE06	Reliability	TA01	Tantalum
RE07	Remote sensing	TE01	Telephony
RE08	Resonance, paramagnetic	TE02	Test-pattern generation
SC01	Scanning tunneling microscopy	TE03	Testing
SE01	Semantics	TE04	Testing, ac
SE02	Semiconductor devices	TE05	Testing, analog signal
SE03	Semiconductor technology	TE06	Testing, chip
SE04	Semiconductors	TE07	Testing, circuit
SE05	Semimetals	TE08	Testing, electron-beam/ion probes
SI01	Signal processing	TE09	Testing, mixed-signal
SI02	Signature verification	TE10	Testing, module
SI03	Silicon	TE11	Testing, optical probes
SI04	Silicon carbide	TE12	Testing, random-pattern logic
SI05	Silicon dioxide	TE13	Text processing
SI06	Silicon oxidation	TH01	Thermal conduction module (TCM)
		TH02	Thermodynamics

TH03 Thickness measurement
TI01 Time-sharing, applications
TI02 Tin
TO01 Topology
TR01 Transistors
TR02 Transmission lines
TR03 Tribology
TY01 Typewriter design
UL01 Ultrasonics
VA01 Vanadium
VE01 Vector processing

VI01 Vibration
VI02 Video signals
VI03 Virtual machines
VL01 VLSI
VO01 Vocoders
WA01 Wave propagation
WE01 Wear
X-01 X-ray diffraction
X-02 X-ray technology
ZI01 Zinc